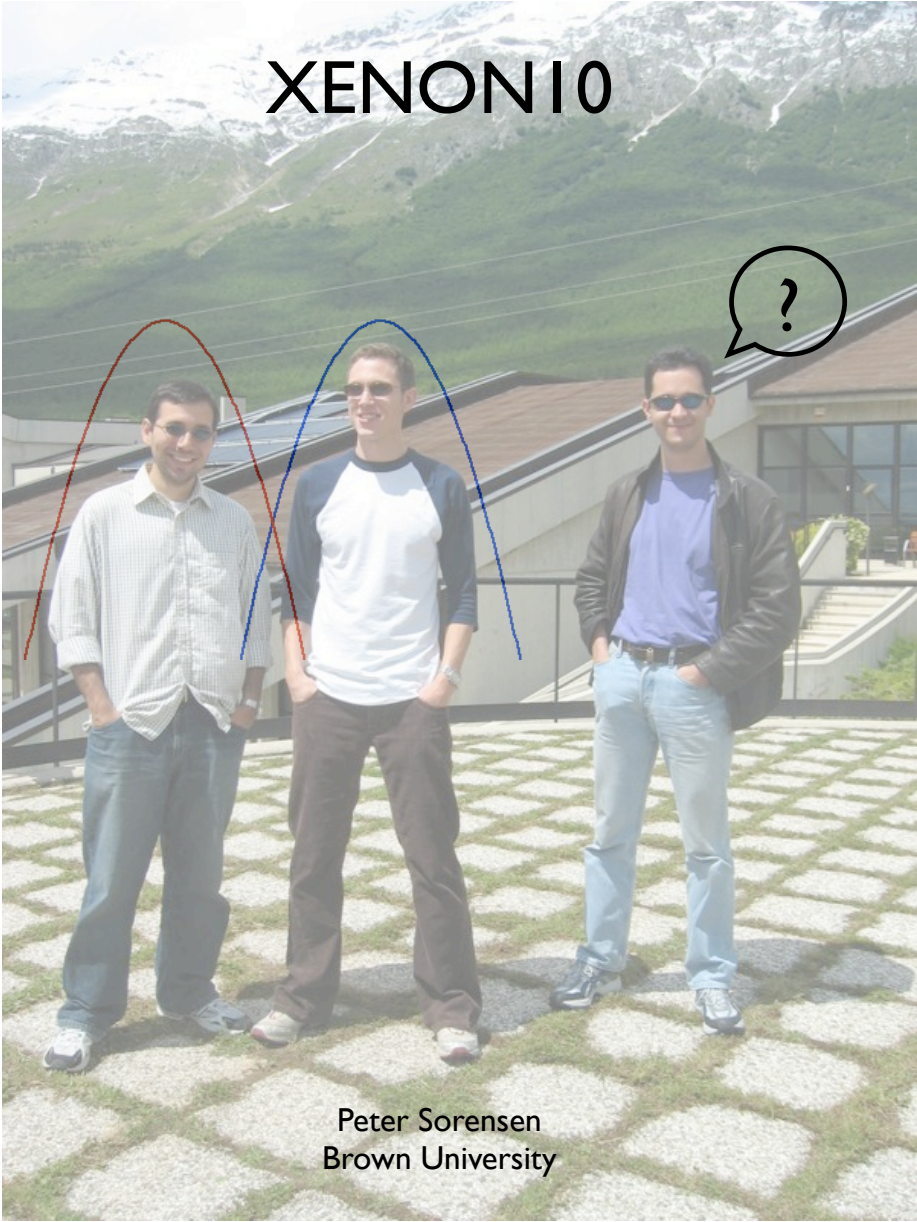


Optimization of Non-Gaussian Background Rejection in



Talk Summary

1. Brief overview of XENON10 installation/detector
2. Trigger Threshold / Analysis Threshold
3. Discrimination of ER v NR: Gaussian & non-Gaussian populations
4. Optimization of discrimination
 - Gaussian: corrections for detector non-uniformity (optimize sigma)
 - Non-Gaussian: identification of anomalous pathologies
5. Discussion of candidate events in XENON10 58.6 Live-Day Result



XENON10 Installation at LNGS

3100 m.w.e. / 20 cm HDPE / 20 cm Pb



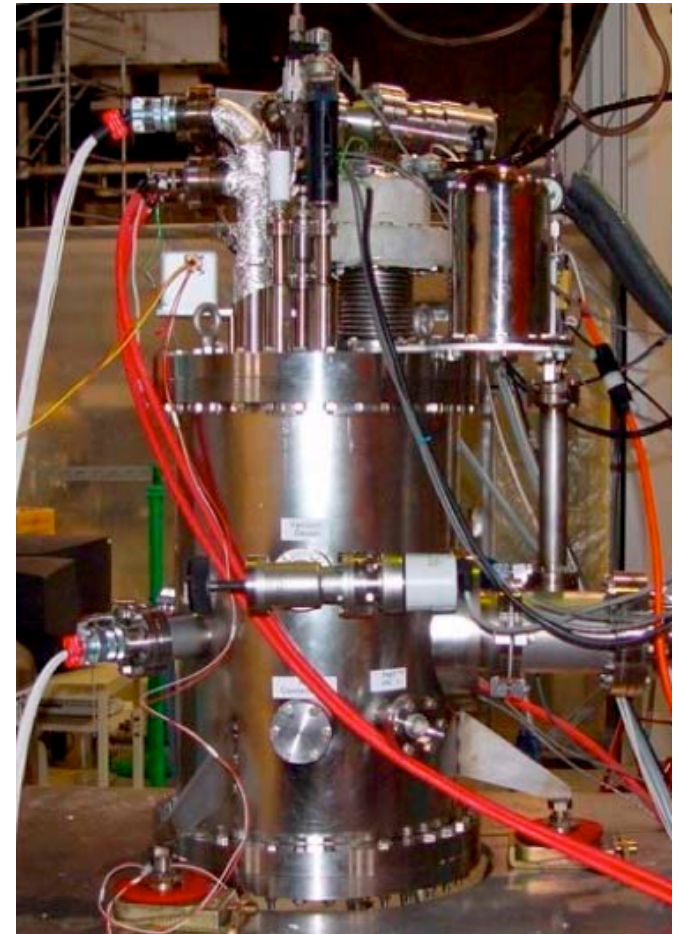
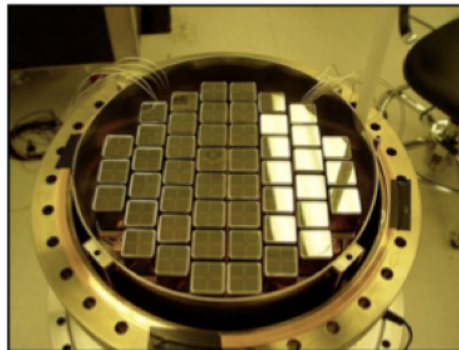
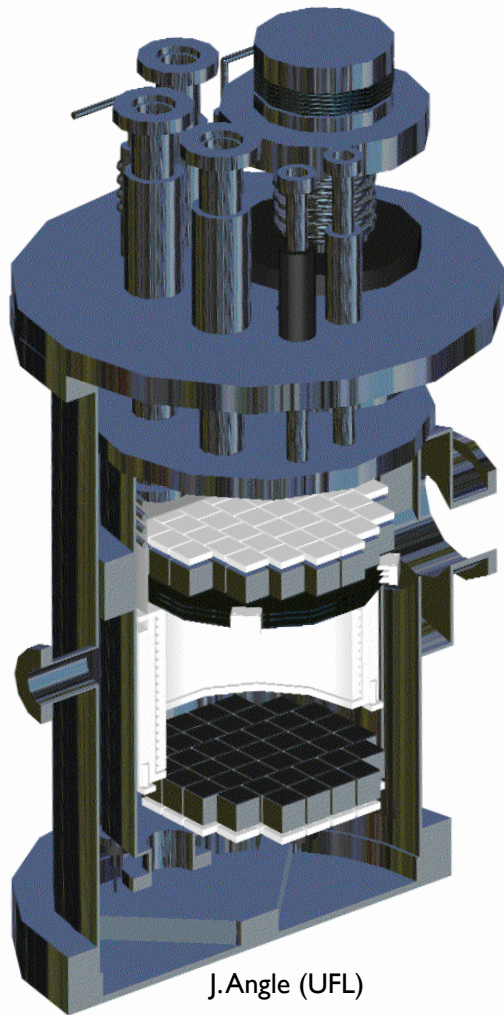
XENON10 Detector

15 cm drift (z) defined by SS mesh grids
20 cm \varnothing defined by Teflon Can
(max 13.5 kg LXe)

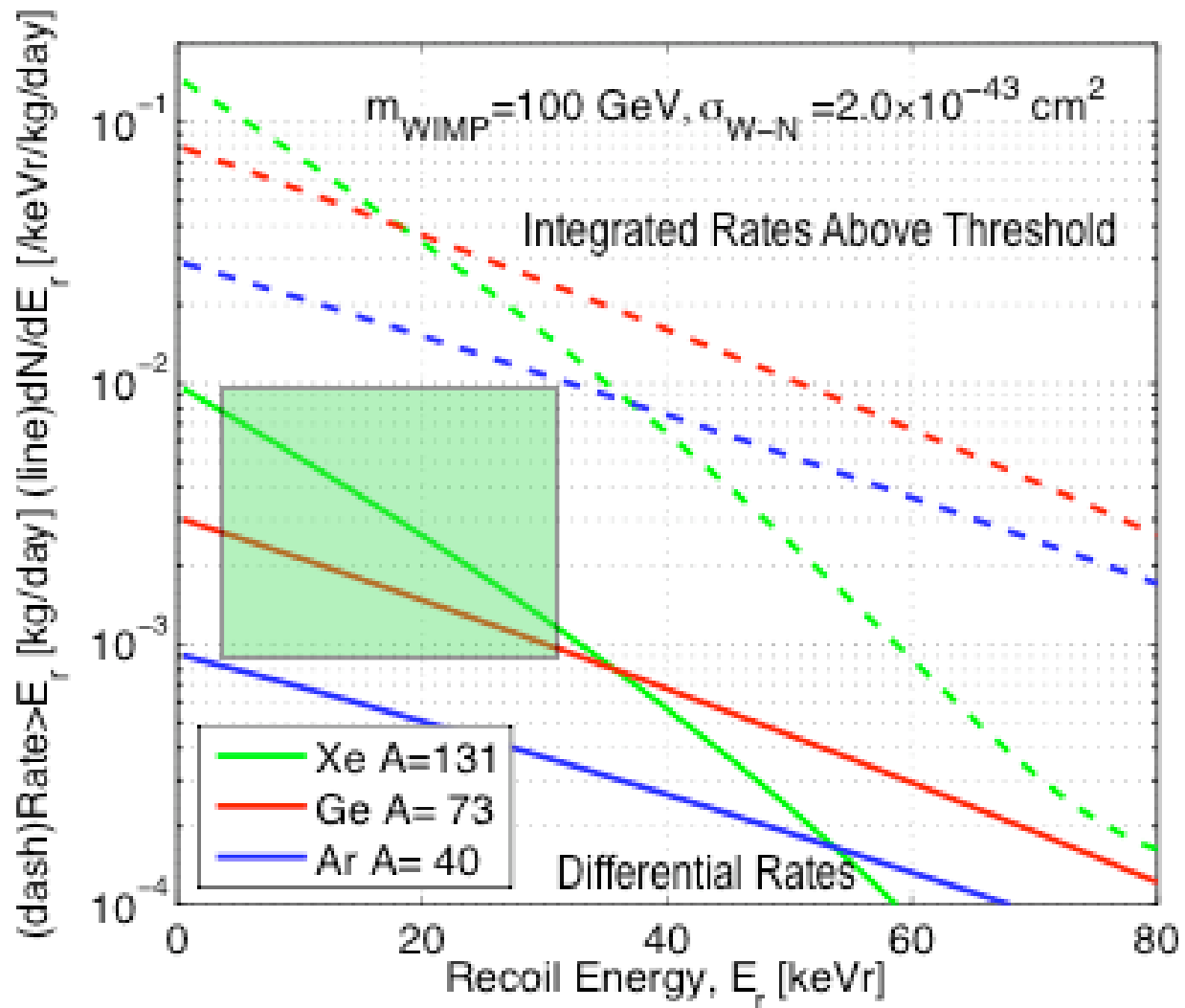
89 Hamamatsu R8520-AL PMTs (1" square)
48 Top Array
41 Bottom Array

Liquid Xe maintained at
 $T=180$ K and $p=2.2$ atm.

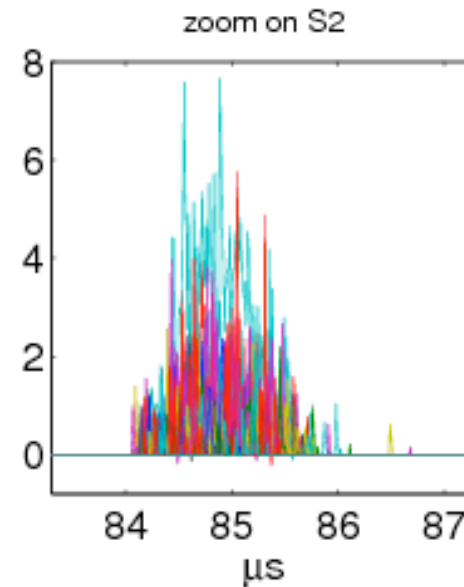
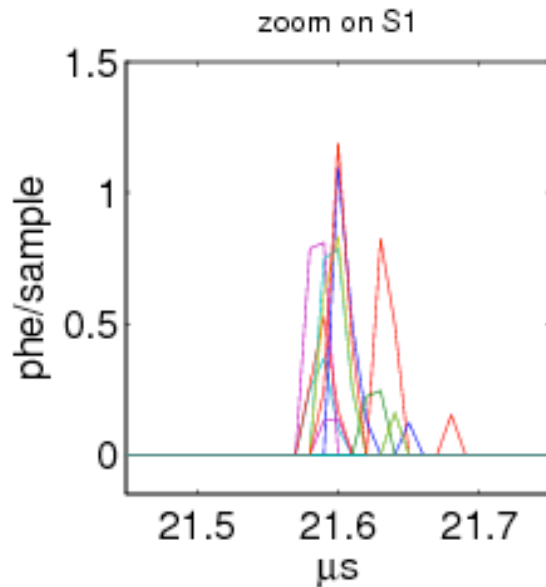
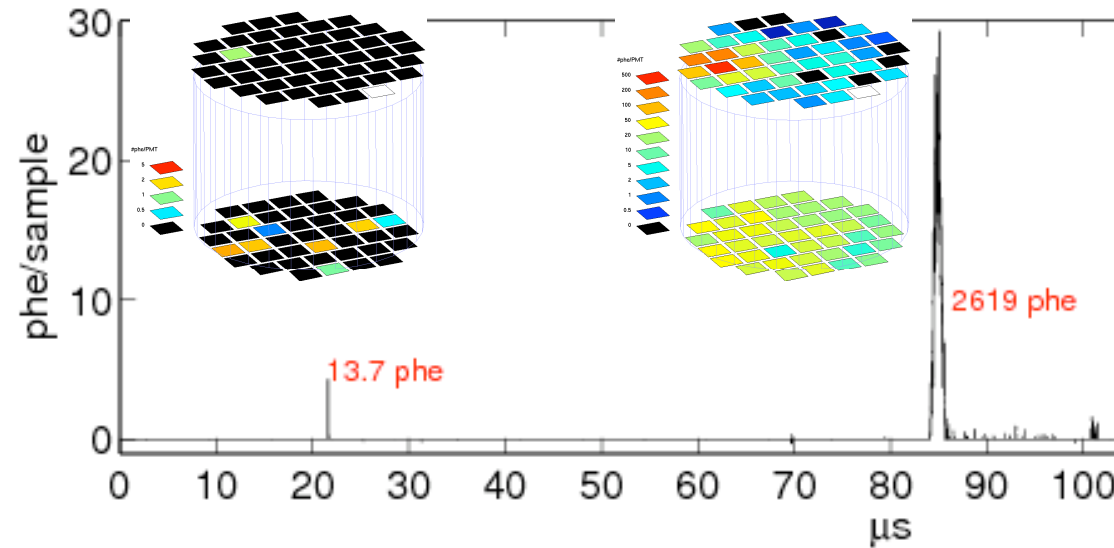
12 kV cathode
 $E_d = 0.73$ kV/cm (drift)
 $E_{gas} = \sim 9$ kV/cm (S2)



Direct Detection Event Rate



Typical Background Event at 4.5 keVee *



S1: primary scintillation

S2: ionization drifted, extracted, amplified in gas region (secondary scintillation)

Background Discrimination:
 $(S2/S1)_{ER} > (S2/S1)_{NR}$

x,y coords. : from S2 Hit-Pattern

z coord. : from drift time Δt
 between S2 and S1

*(scaled using 3.0 phe/keVee from 122 keV gamma cal.)

Trigger Schemes

SI Trigger:

1.

- (1) n-fold coincidence in 80ns window
- (2) 80% single photo-electron acceptance
- (3) 80% light on bottom (trigger) PMTs

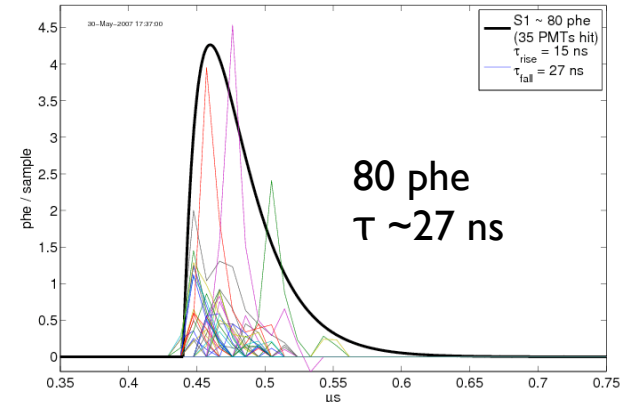
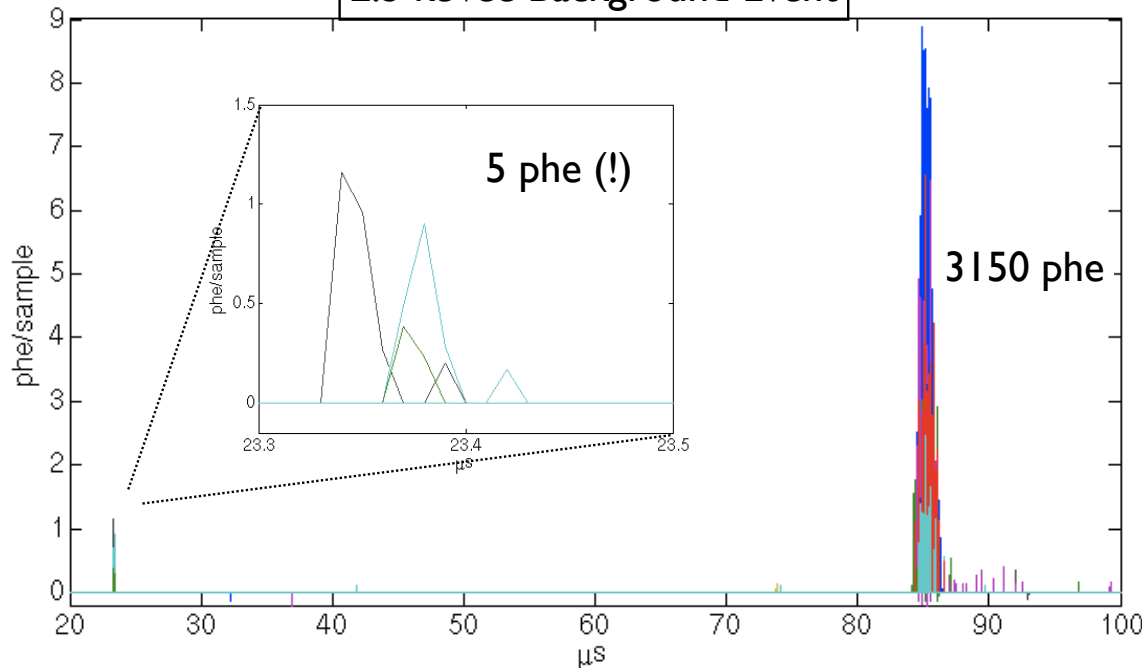
S2 Trigger:

2.

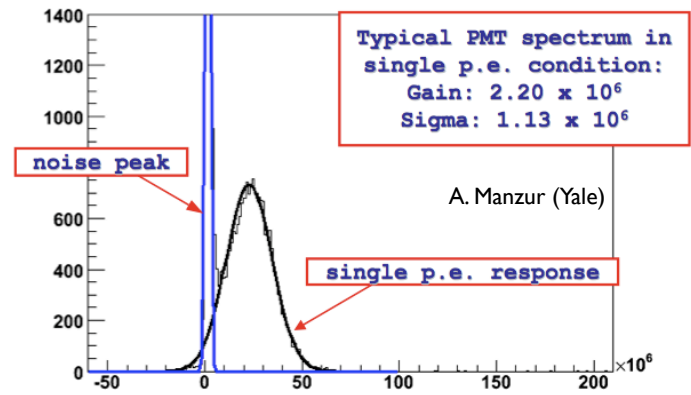
- (1) $\Sigma(34 \text{ top-center PMTs})$
- (2) integrate with $\tau = 1 \mu\text{s}$
- (3) threshold discriminator

(Final Trigger Solution)

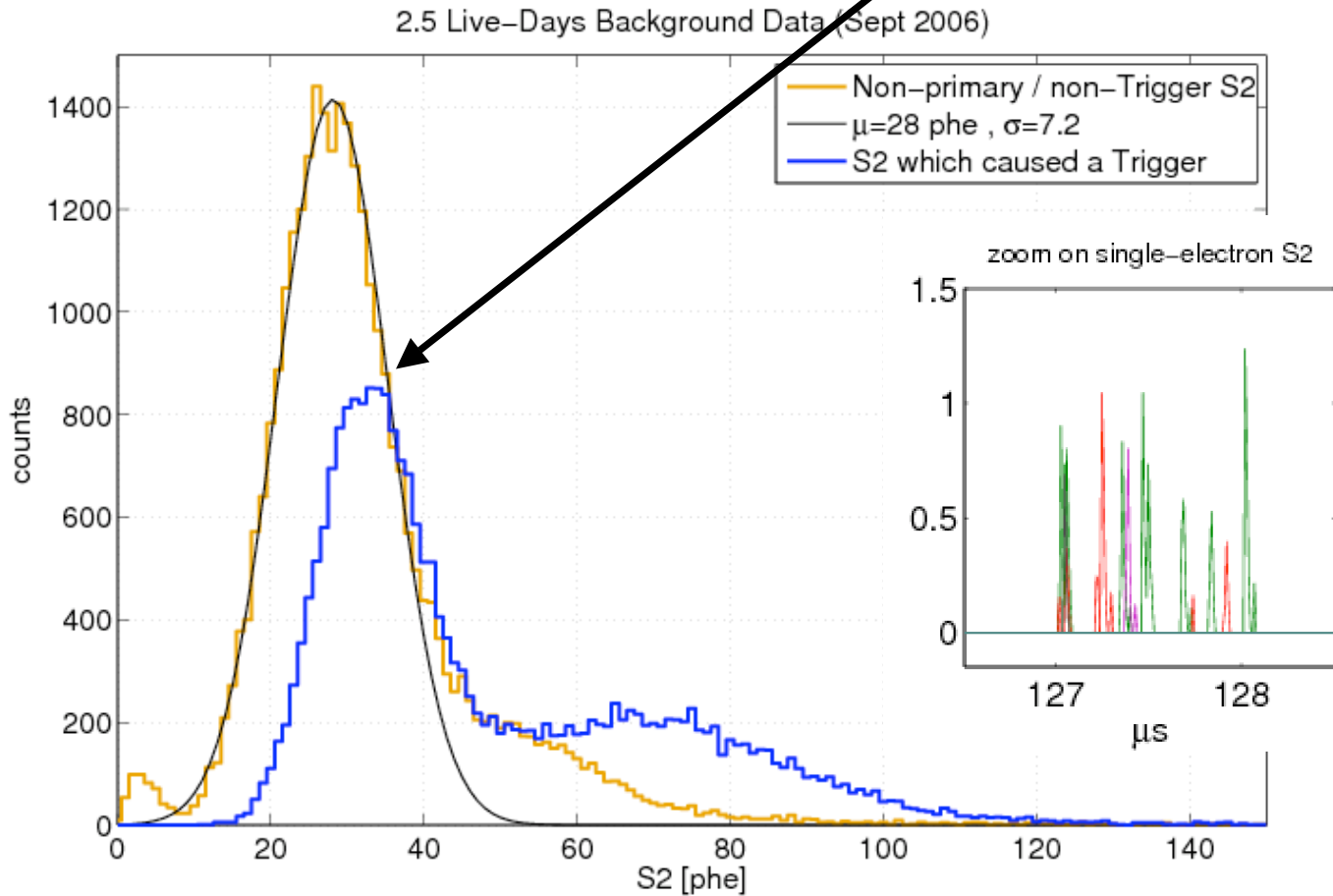
2.3 keVee Background Event



150 ns



S2 Trigger Threshold: single electron (!)



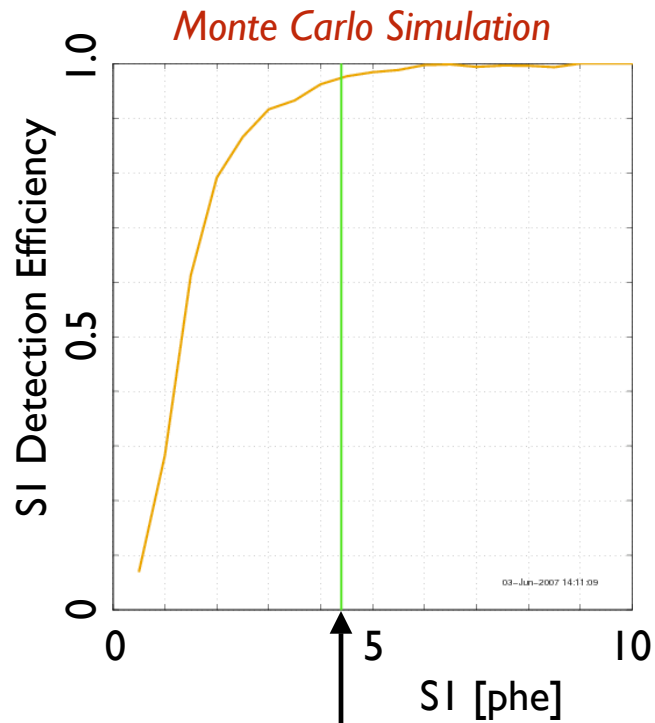
Typical S2 at threshold:

ER (2 keVee):
2800 phe (~100 e-)
NR(4.5 keVr):
1100 phe (~40 e-)

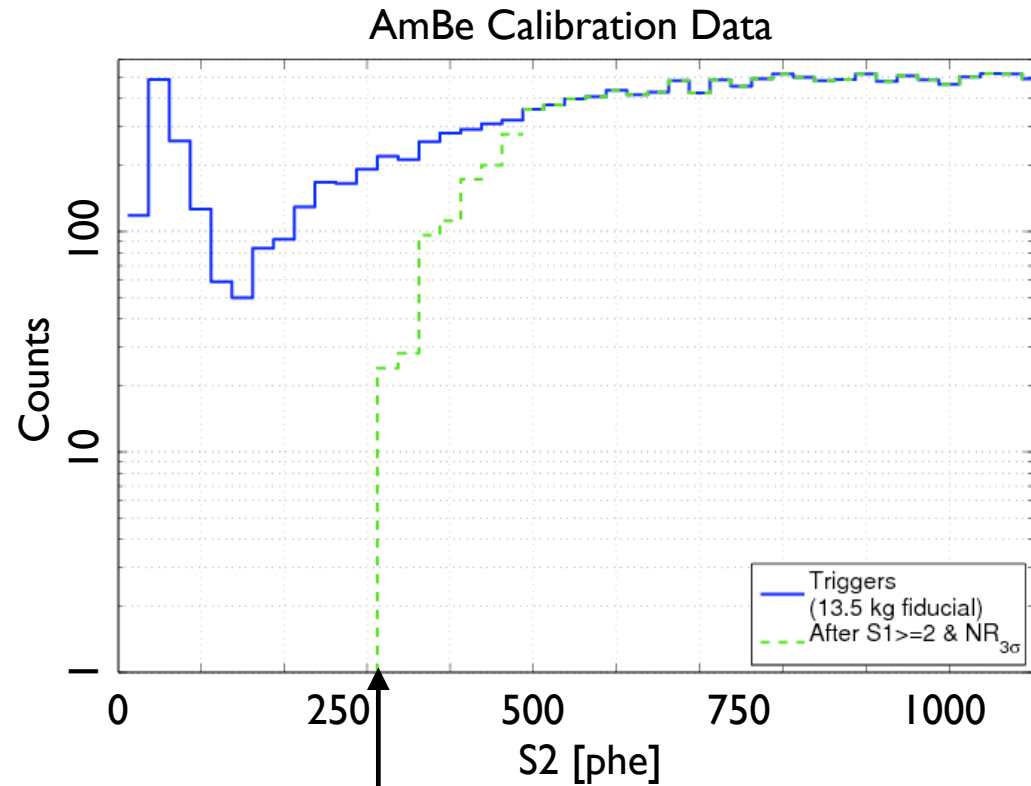
Smallest NR S2 at 4.5
keVr threshold:
300 phe (~12 e-)

Non-primary S2 => found in event waveform, not necessarily correlated with event energy deposition
Rate ~ 0.17 Hz

Analysis Threshold \gg Trigger Threshold

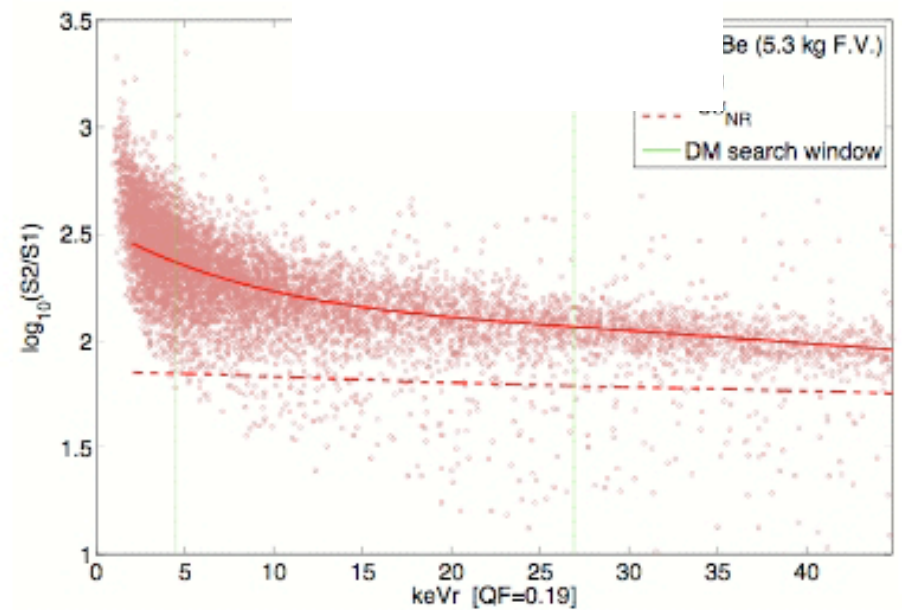
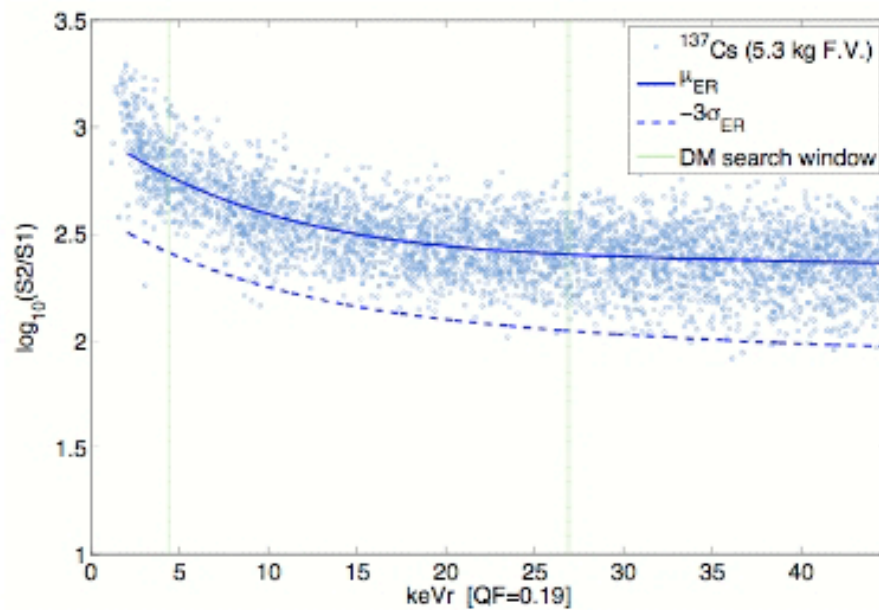


SI-lookback
efficiency ($n \geq 2$)
from MC :
~ 99% at 4.5 keVr

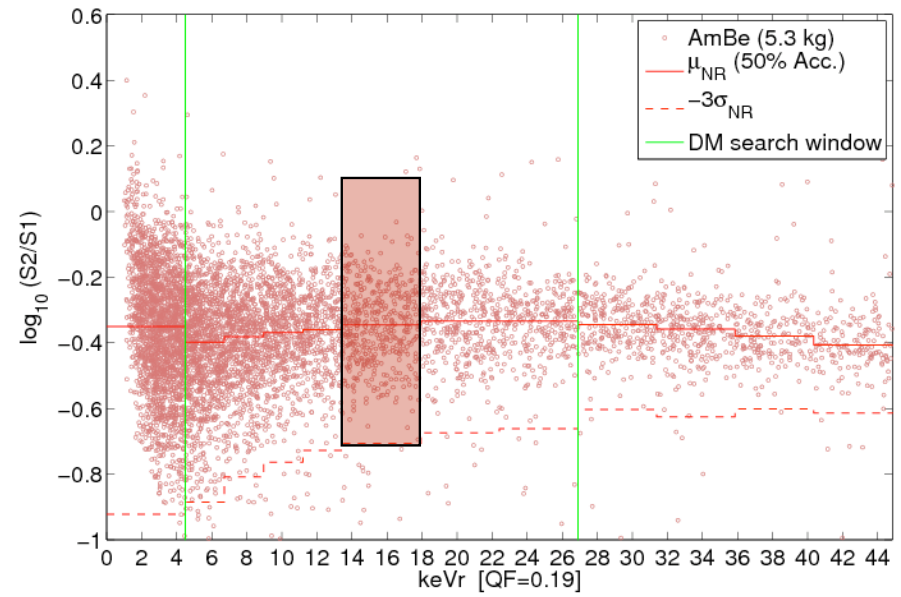
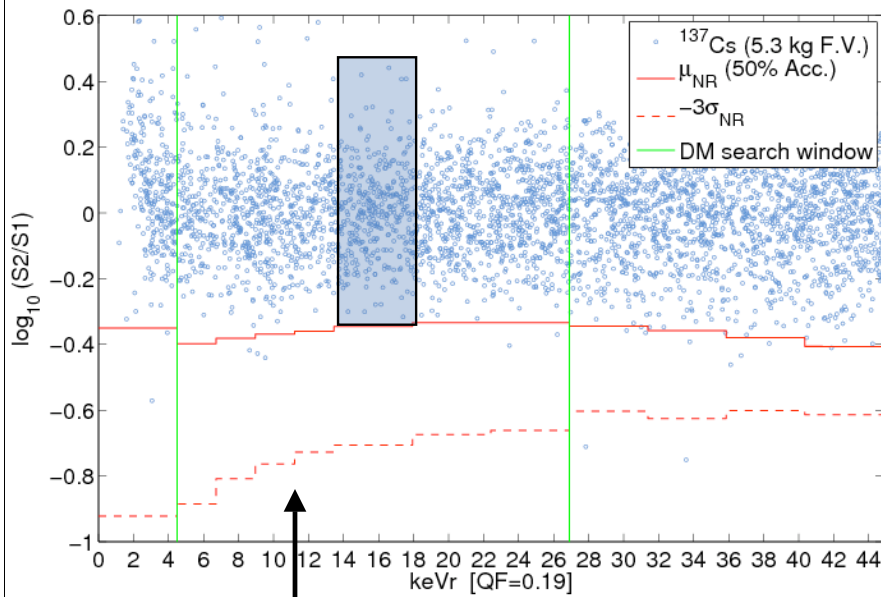


Effective S2 **analysis** threshold ~ 300 phe
(12 e-) set by S1 coincidence req. ($n \geq 2$)
and NR -3σ contour

Calibration Data Band Centroid / -3σ



For DM-Search Analysis

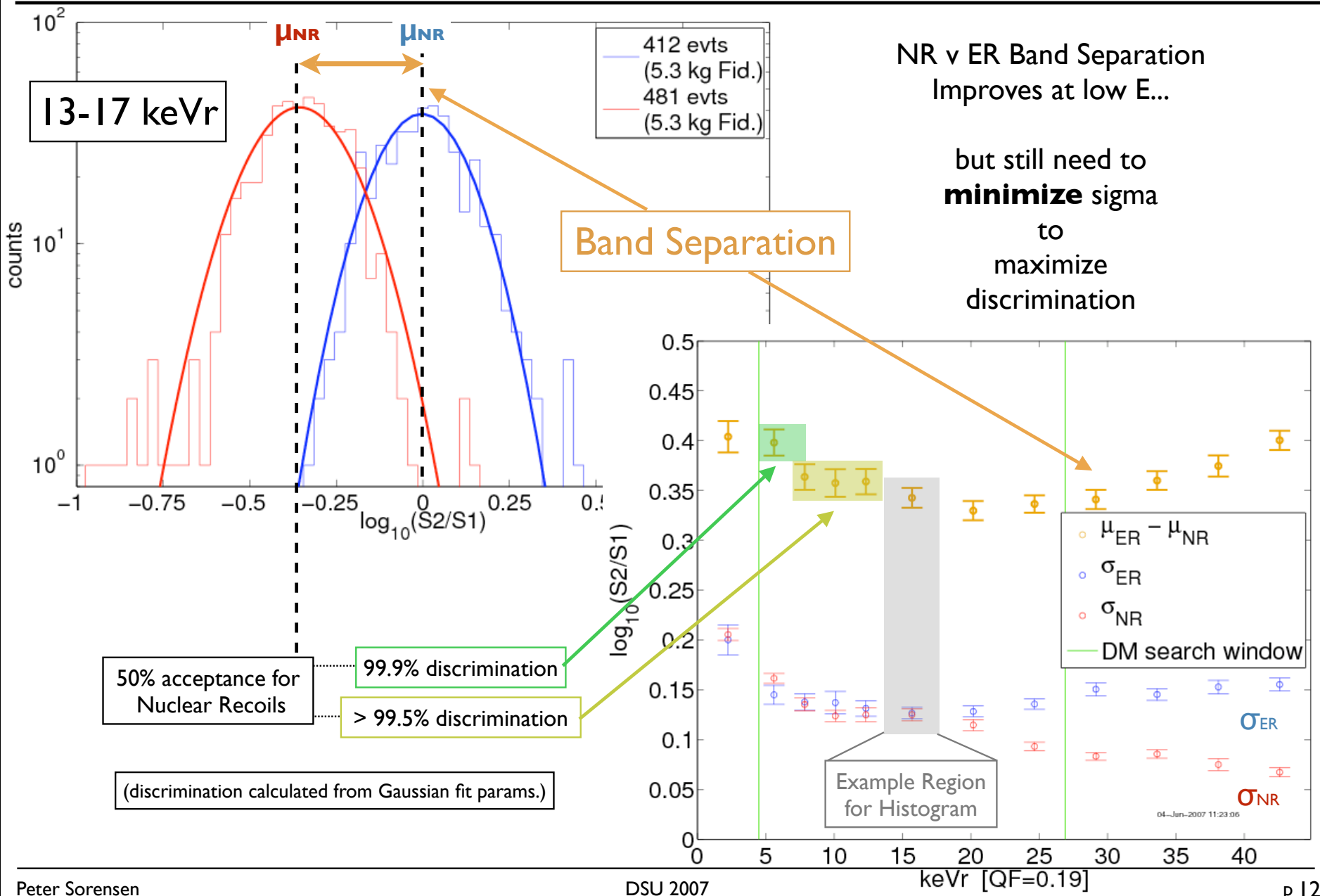


because ionization yield rises at lower energy

Make a simple coordinate transform (based on μ_{ER})
to remove energy-dependence

DM-Search acceptance box in discrete bins

Discrimination Parameter appears Gaussian



Corrections to data improve sigma

$\pm 20\%$ variation in S2
across x-y

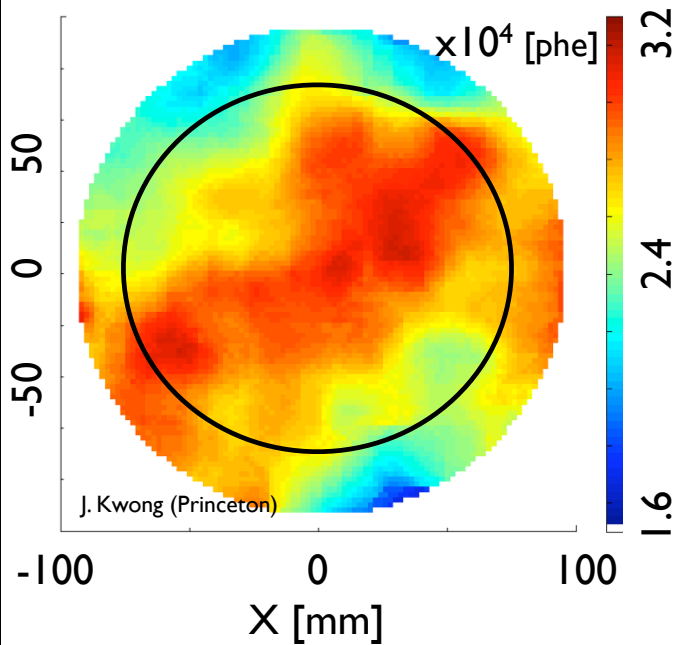
($\pm 25\%$ in Full Volume)

$\pm 10\text{-}15\%$ variation in
Relative Sensitivity

$\pm 22\%$ variation in
S1 across z

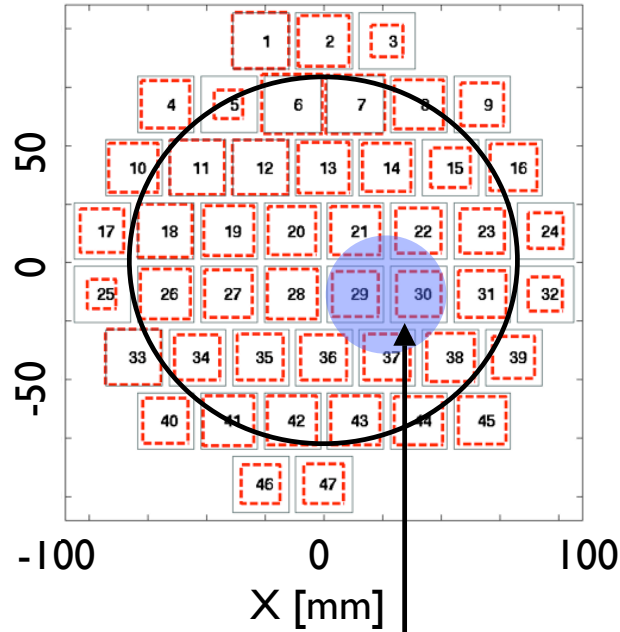
($\pm 28\%$ in Full Volume)

S2 Variation: 40 keV line



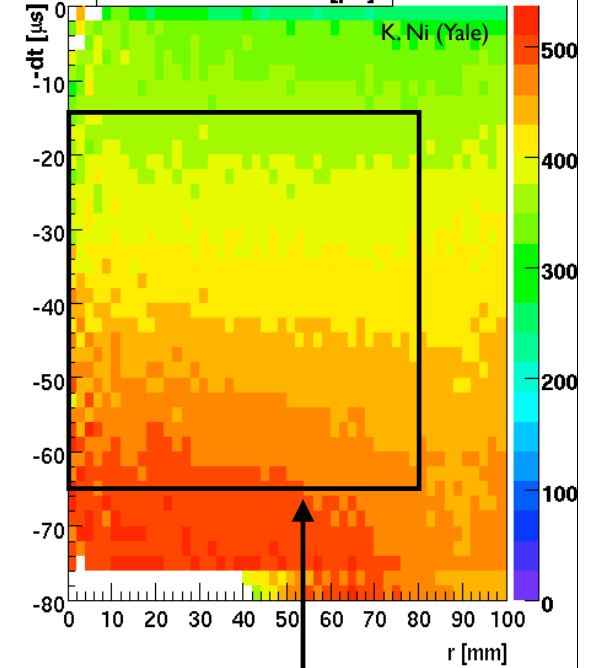
< 2% variation in S2 with z
(electron lifetime > 2ms)

Top PMT Array Relative Sensitivity



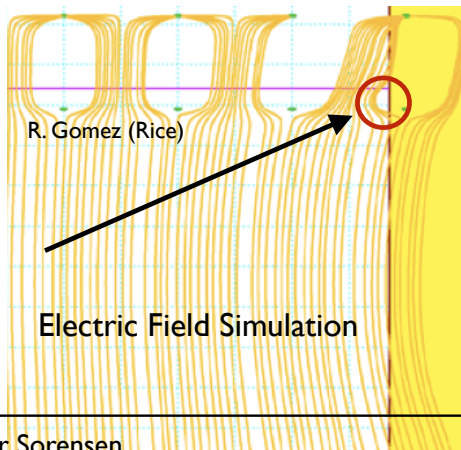
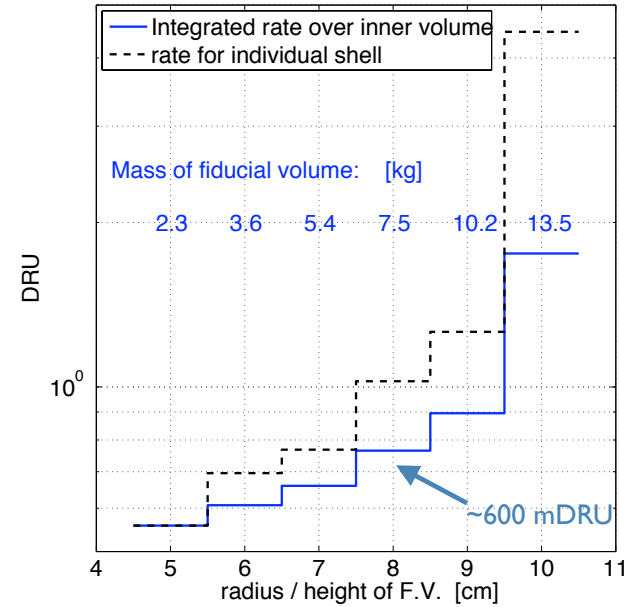
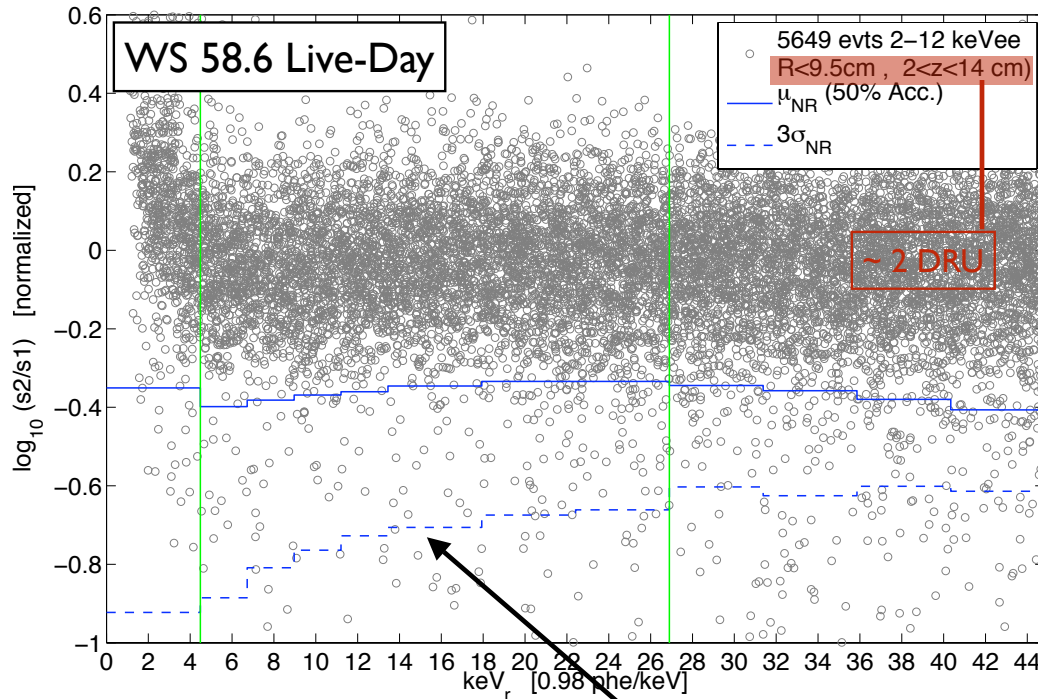
R.S. map obtained by comparing S1
signal in each nearest-neighbor pair,
then diagonalizing the matrix

S1 for 164 keV line [pe]



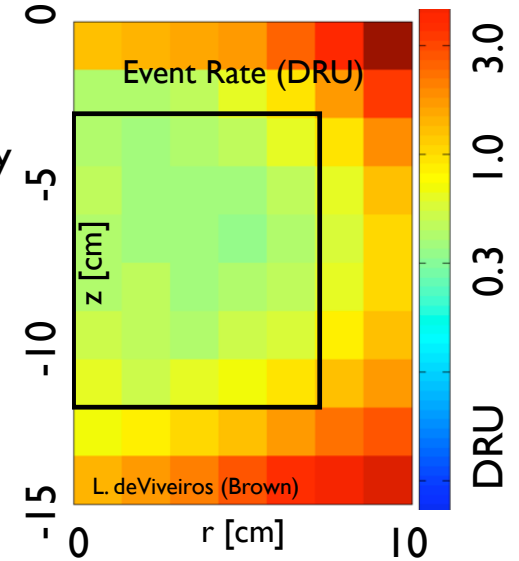
Fiducial Volume

Before Fiducial Volume Cuts

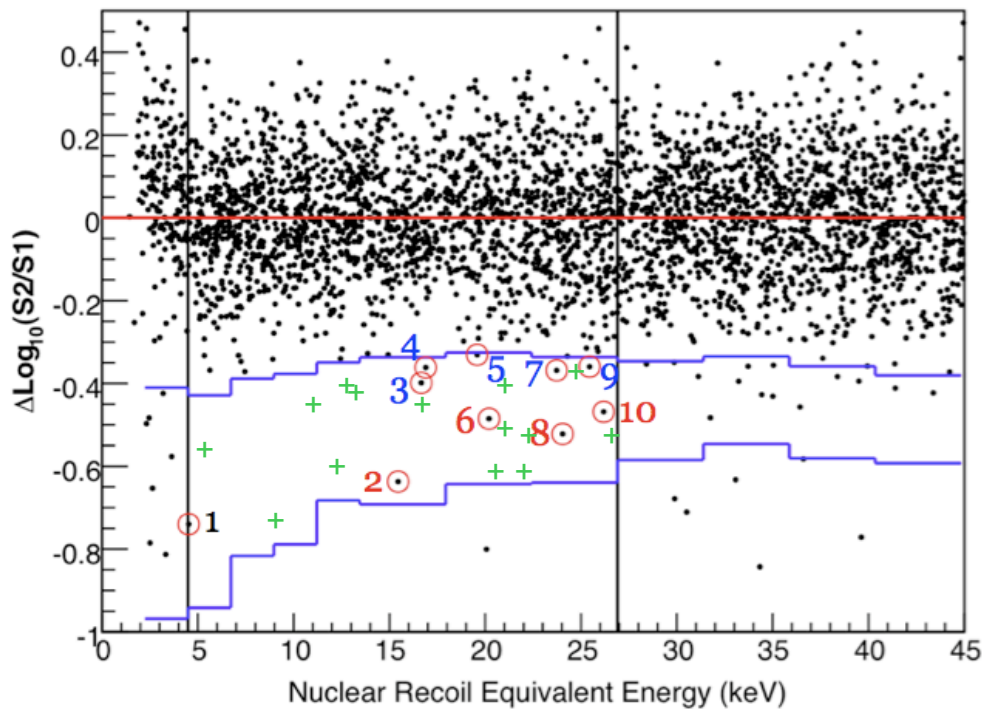


$$\text{DRU} = 1 \text{ cts/keVee/kg/day}$$

Most (spurious) events in box are removed by Fiducial Volume Cuts



After Fiducial Volume Cuts



still have 23 events (a significant fraction appear non-Gaussian).

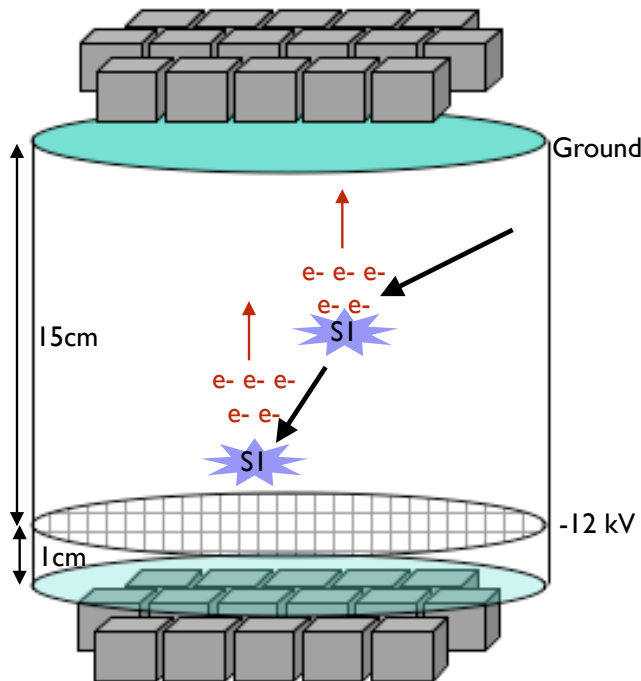
13 events (+) removed by (primary analysis) cut targeted at anomalous SI hit-pattern

origin of **non-Gaussian** tails in ER distribution:
Gamma X events

Gamma X: what is it? →

a multiple scatter in which the S2 from one of the scatters is absent

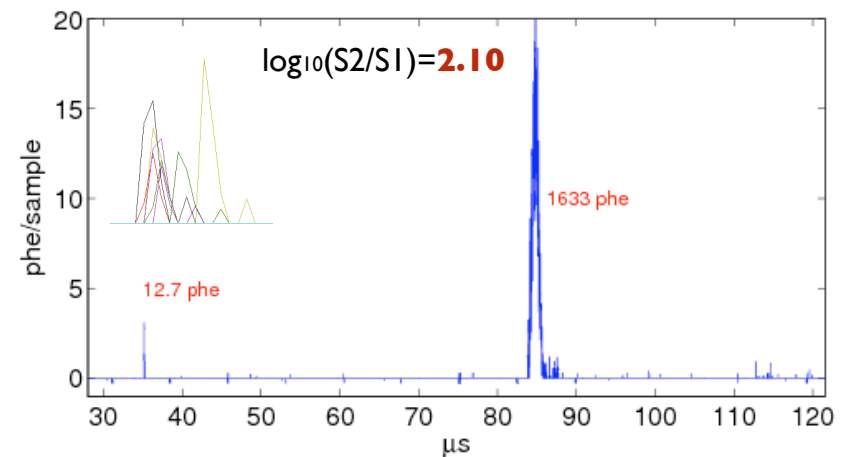
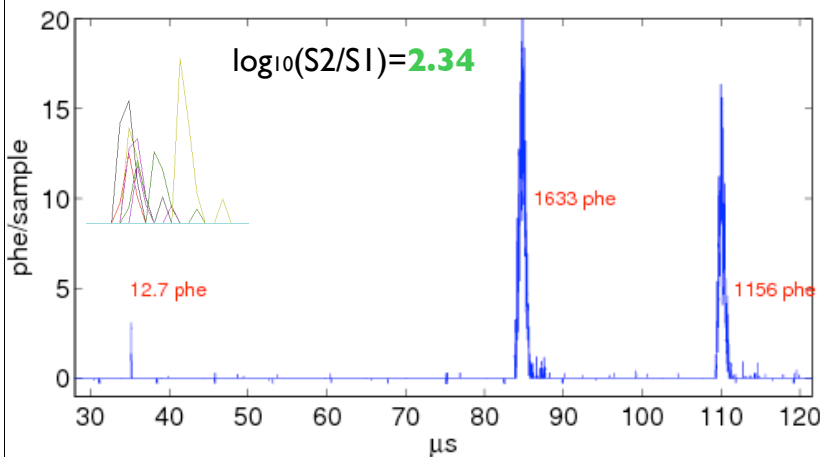
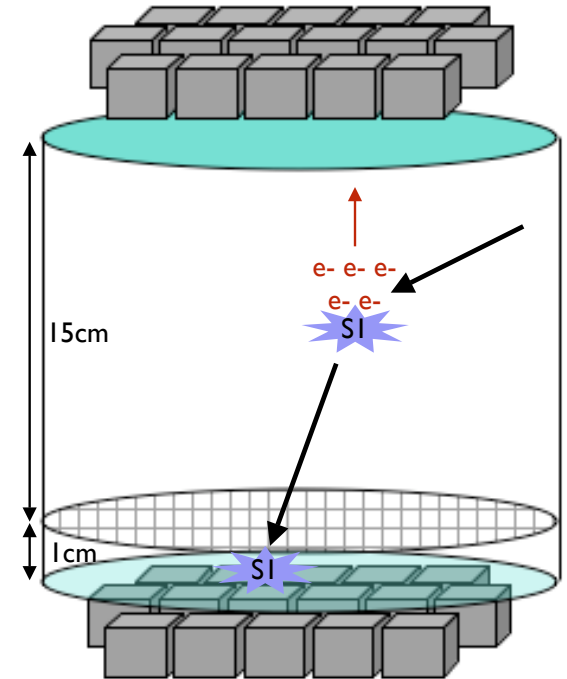
normal multiple scatter



Example:
if the 2nd scatter happened **below** the cathode grid, its S2 would be **absent**.

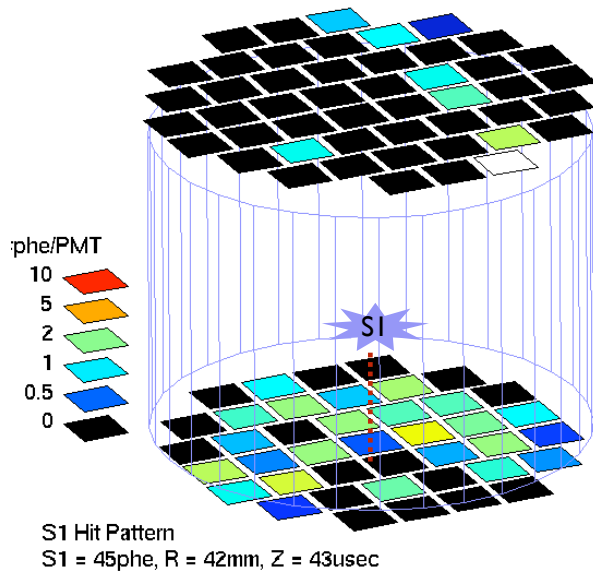
Result:
S2/S1 **decreases**, which can make an electron recoil look like a nuclear recoil

Gamma X multiple scatter

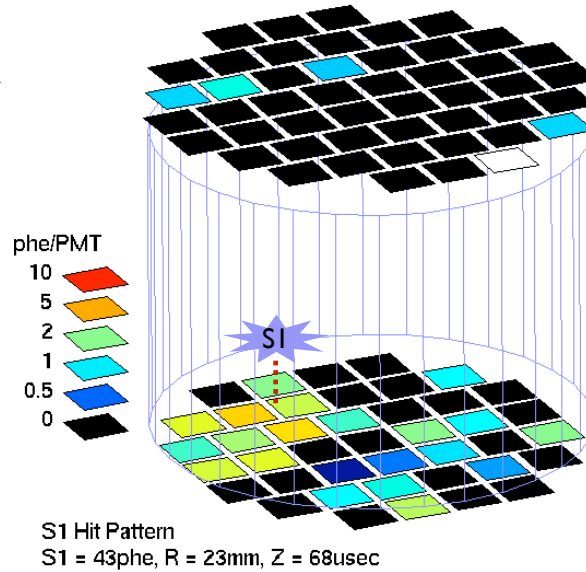


How to spot a Gamma X Event: SI Hit-Pattern

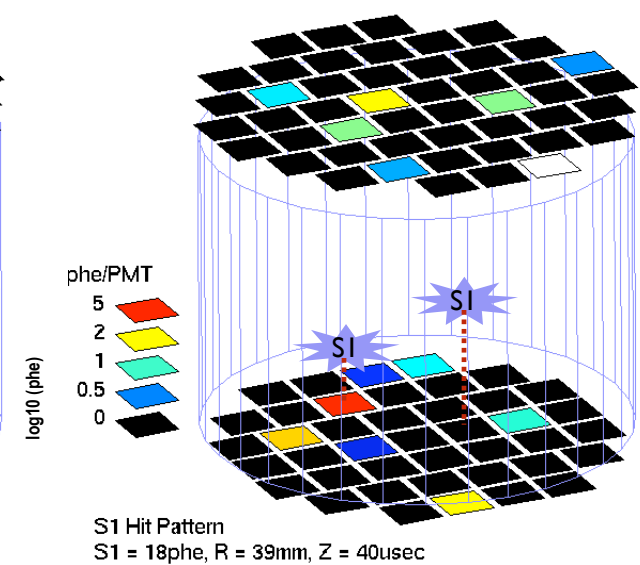
Scatter in center of FV



Scatter close to bottom of FV



Gamma X scatter



Events in Fiducial Volume =>
diffuse Hit Pattern

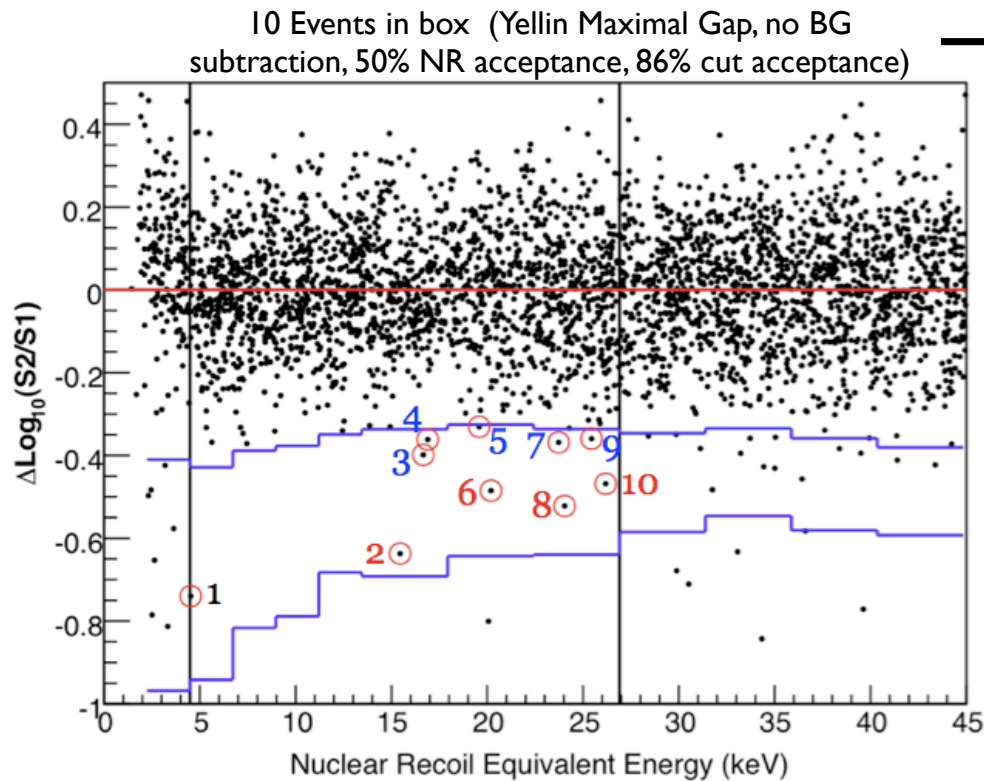
Events near bottom => more
localized Hit Pattern

Events below cathode => highly
localized Hit in ~ 1,2 PMTs

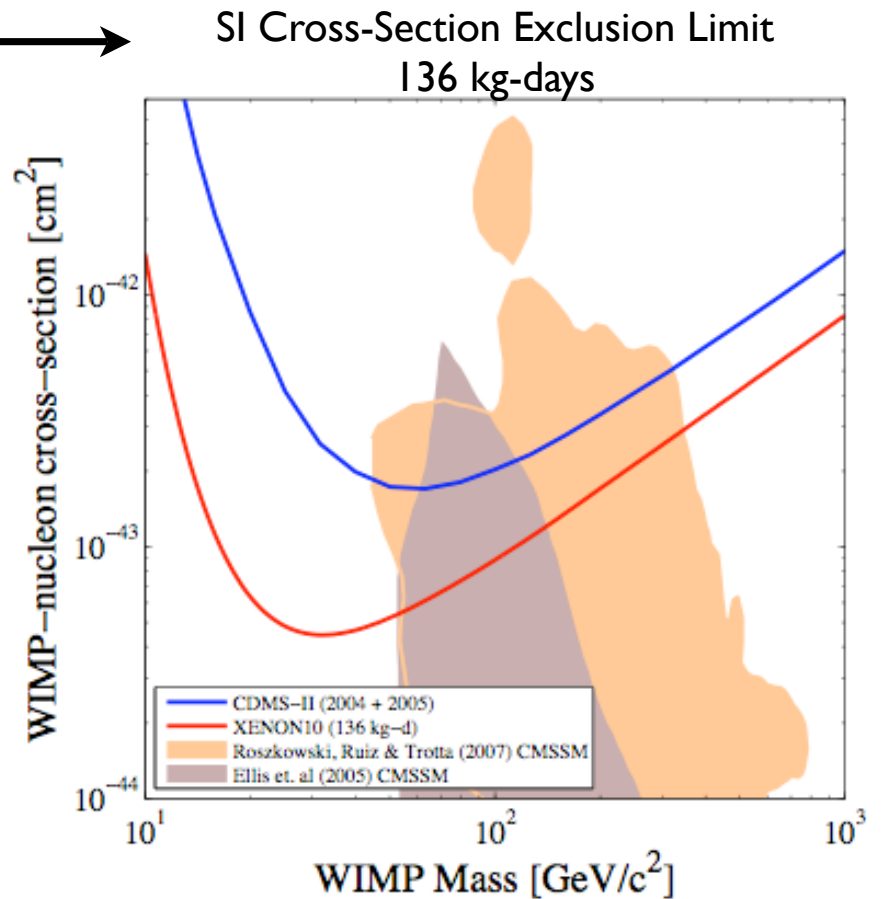
Primary Analysis Gamma X cut:

$$S1_{RMS} = \sqrt{\frac{1}{n} \sum (S1_i - \overline{S1})^2}$$

XENON10 58.6 Live-Day Result

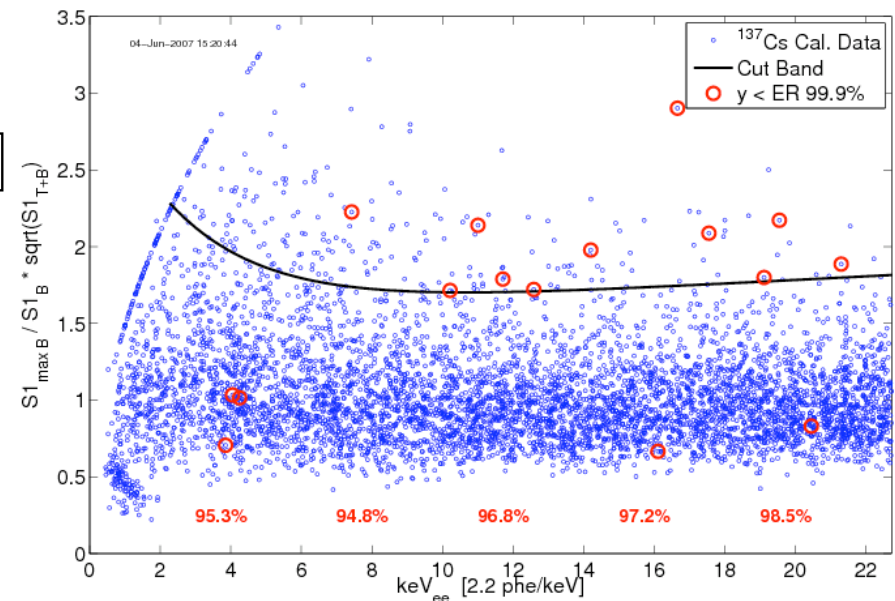
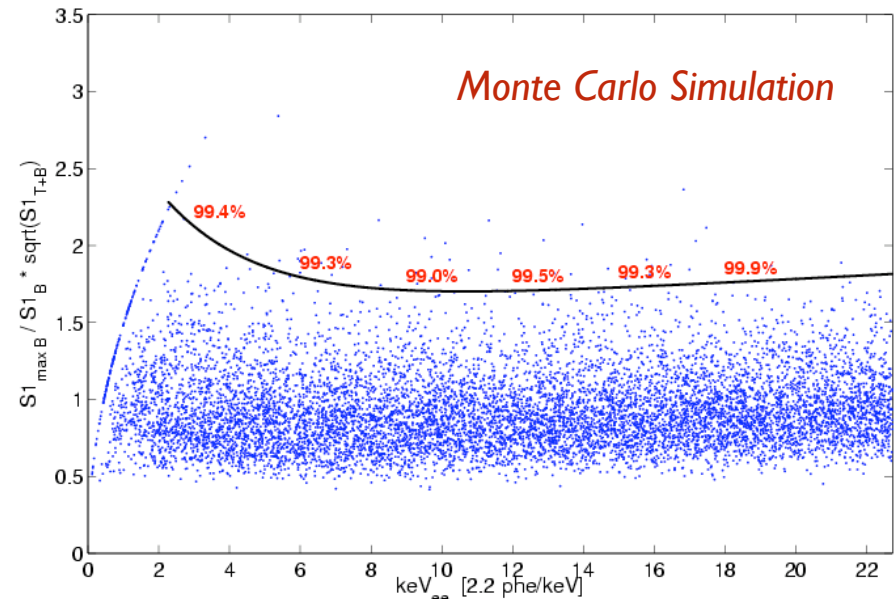
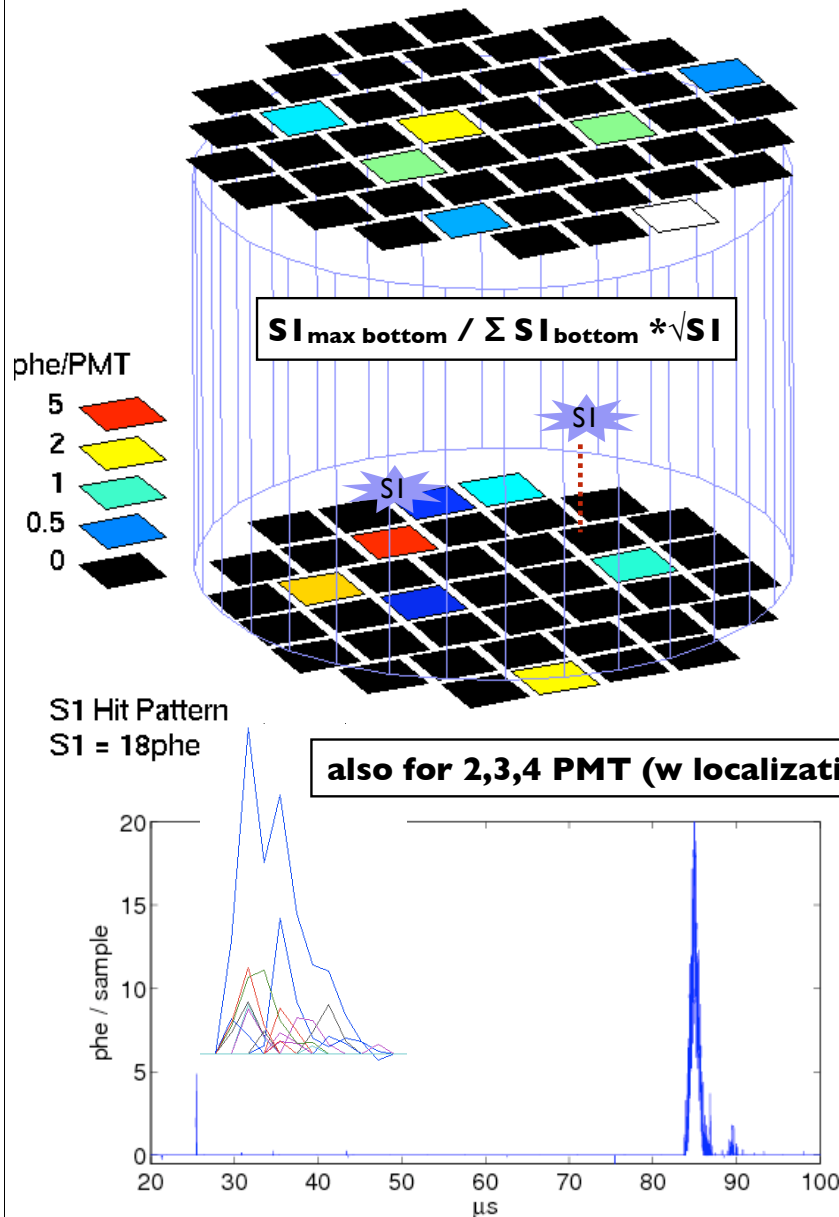


Events remaining in box
are NOT dark matter...
they are **Gamma X**
events



A More Sophisticated Gamma X Cut

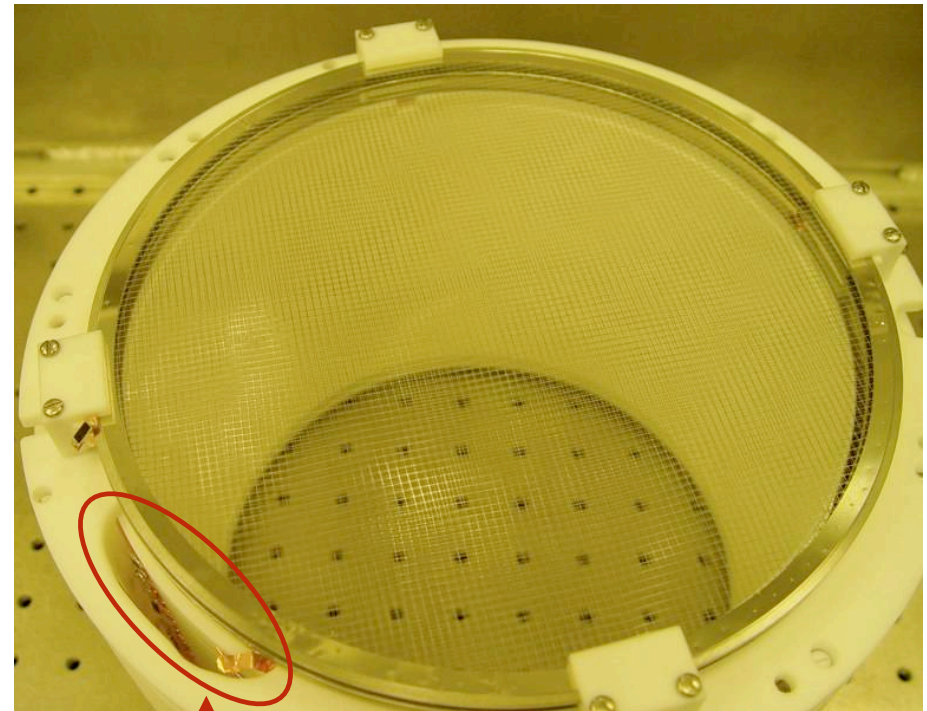
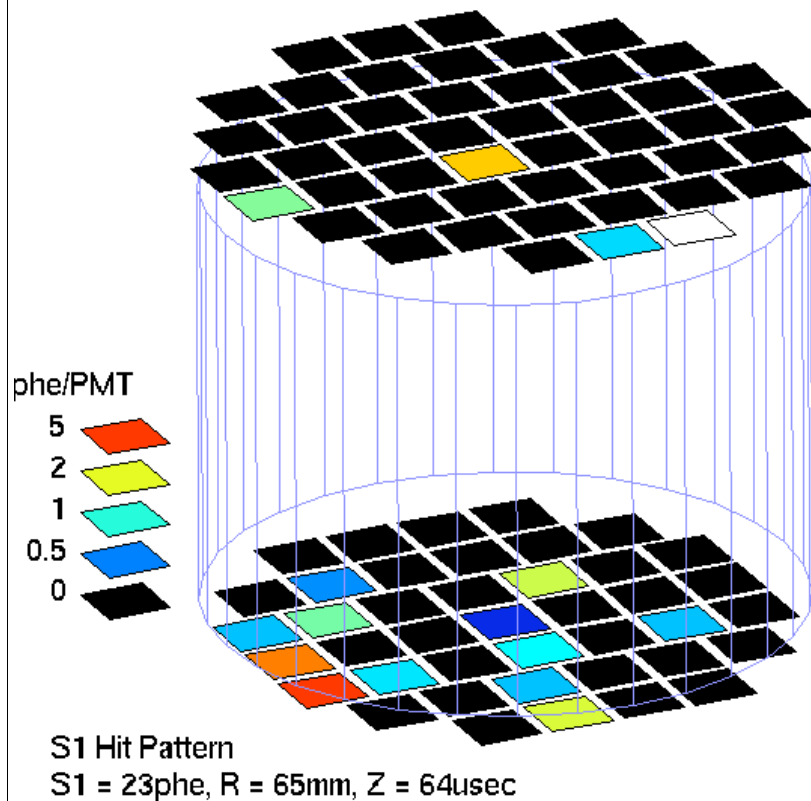
cuts developed as part of an independent (secondary) blind analysis



Identifying Anomalous Topologies

Subset of Gamma X events with
signal concentrated in 2 PMTs:
Resistor-Chain Events

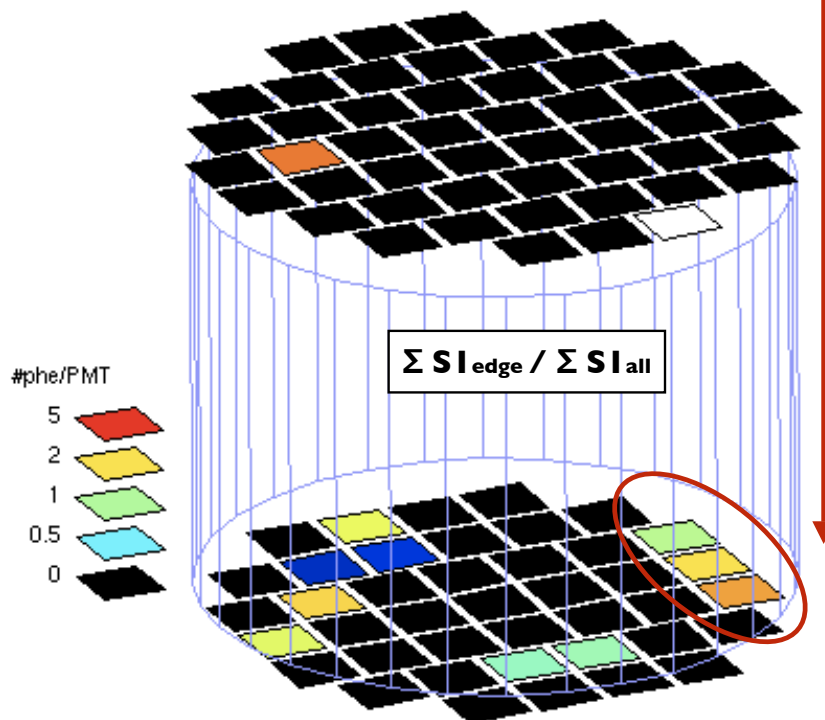
Rare Effect: ~ 10 events in
combined WS background data + Cs
calibration data (175 Live-Days
Equivalent)



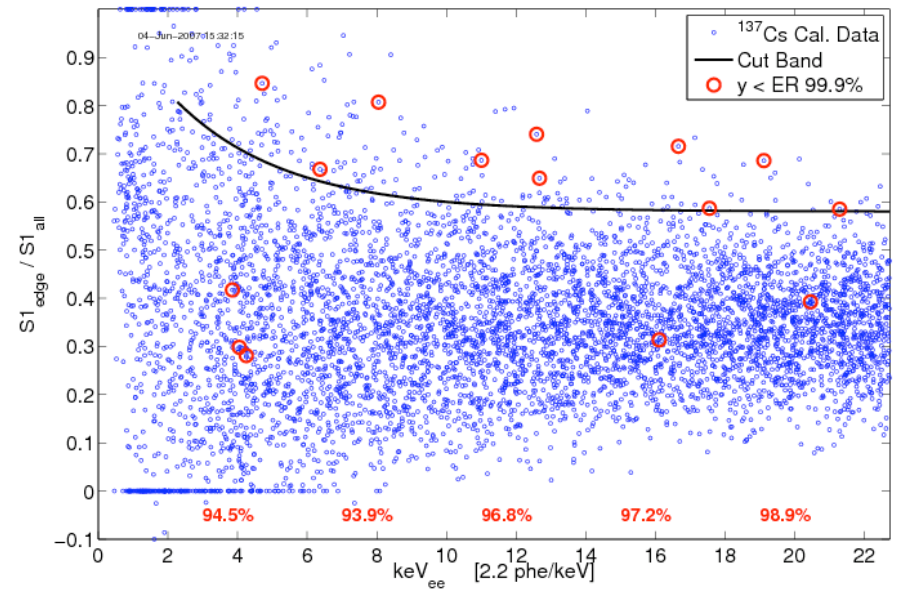
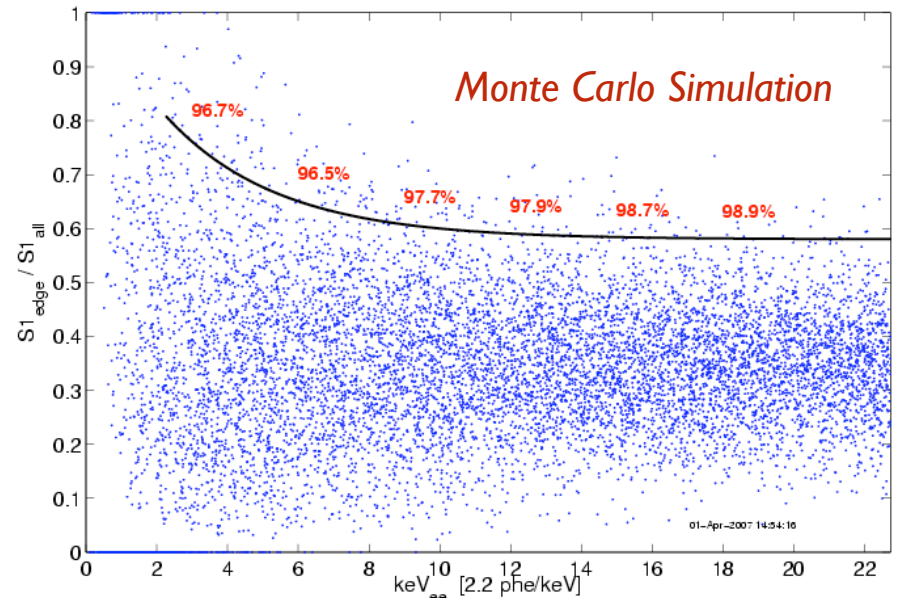
Resistor-Chain (for drift E-Field)
Pocket is filled with LXe

Edge Gamma X Events

Subset of Gamma X events with signal concentrated in **Edge** PMTs



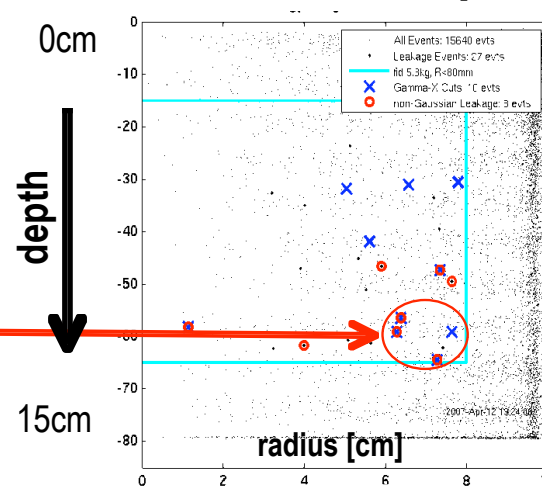
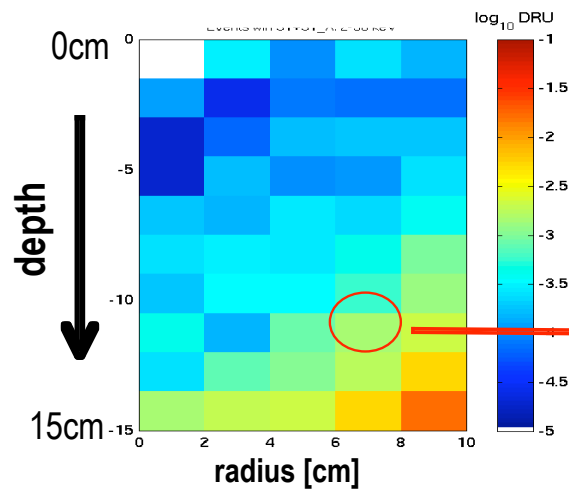
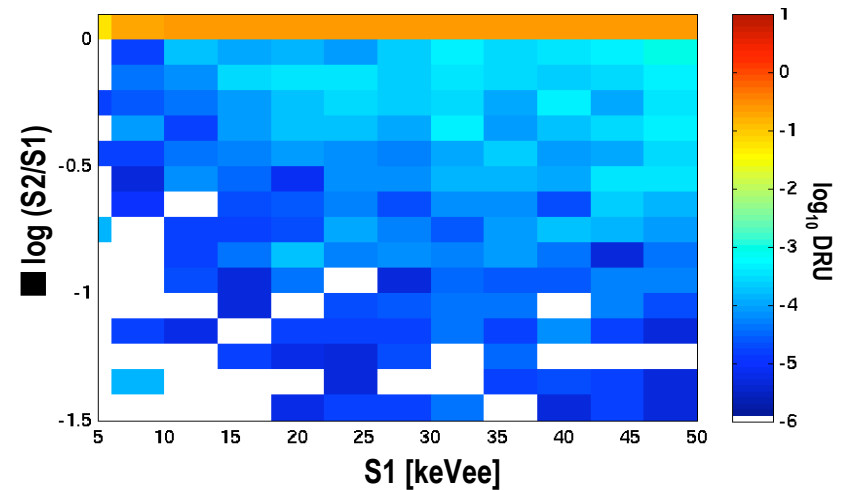
could indicate a 2nd scatter near edge of the detector, where there are regions of reduced/zero drift field



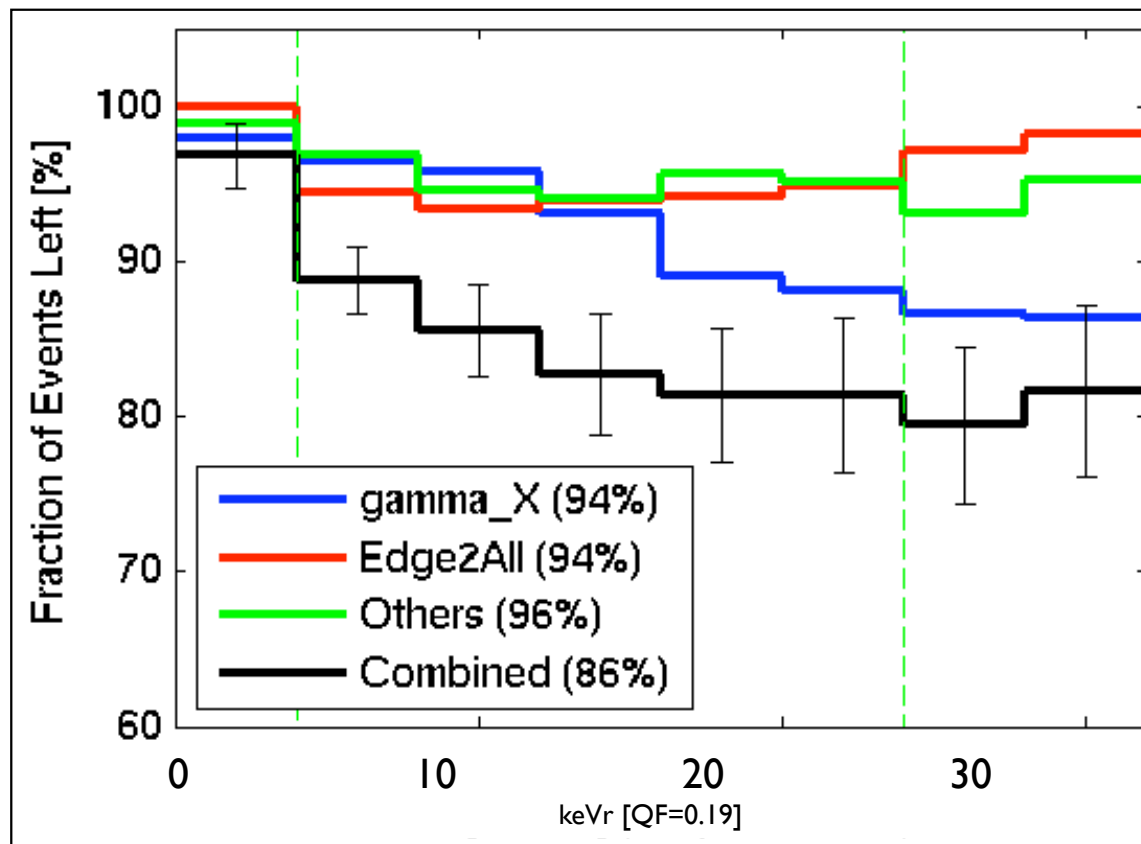
Gamma-X Monte Carlo

- We have simulated the expected Gamma-X background due to gammas generated in the detector (i.e. PMT radioactivity)
- We have found the rate for **Reverse Field Region** Gamma-X events to be sub-dominant for our ER vs NR discrimination – their rate at low energies (<25keV) is **1mdru** or less.
- Comparing the spatial distribution of events
 - 10^{-3} DRU x 10keVee x 5.3kg x 59livedays = ~3 events

Simulated Gamma-X Spectrum with Secondary Scatters on the Reverse Field Region (for expected Gamma Background)

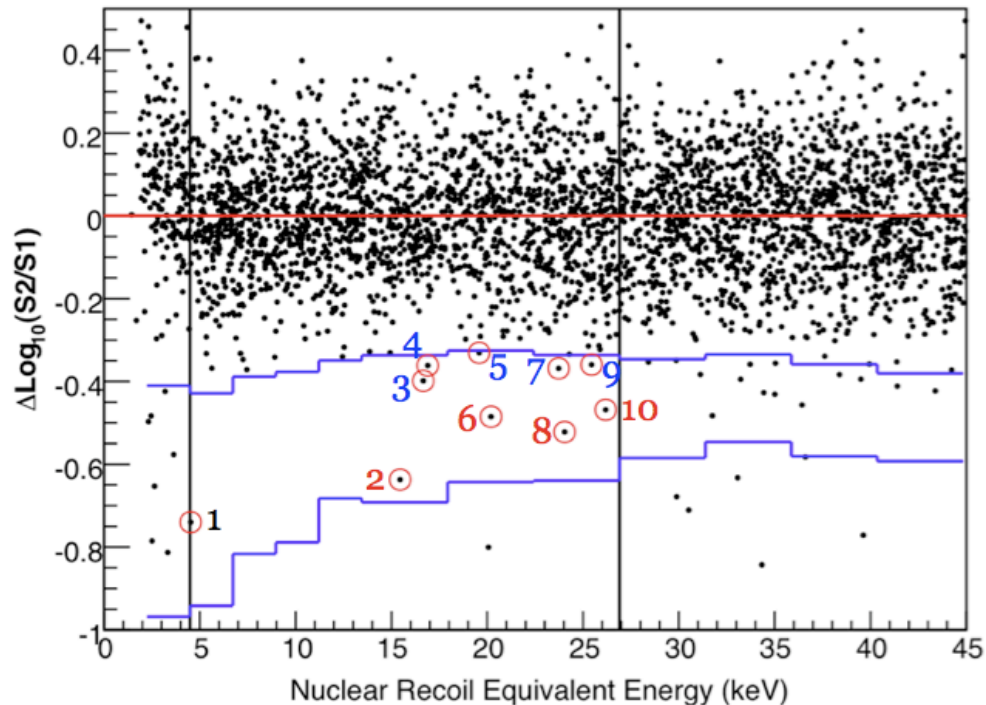


Cut Efficiencies for AmBe NR Calibration Data



Efficiency shown for secondary analysis (primary analysis is within 1%)

Summary



☞ 10 Events in box:

5 are consistent w Gaussian ER background
5 are NOT.

☞ events 1,6,8,10 **removed** by Secondary (blind) Cuts:

- #6: Gamma X (Resistor-Chain Hit-Pattern)
- #8: Gamma X (Resistor-Chain Hit-Pattern)
- #10: Gamma X (Anomalous Edge Hit-Pattern)
- #1: Coincidence $n=1$ (Requirement: $n=2$)

☞ event 2 **almost** removed by Secondary (blind) Cuts:

Gamma X (signal concentrated in 3 PMTs)
a posteriori 1% decrease in acceptance => would have been cut

Discrimination challenges we can certainly overcome:

☞ Maximize discrimination against Gaussian leakage by correcting for instrumental (detector) variation (x,y,z position / PMT)

☞ Non-Gaussian Pathologies seem to arise predominantly from “dead” regions of LXe

XENON10 Collaboration

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Case Western Reserve University Tom Shutt, Paul Brusov, Eric Dahl, John Kwong and Alexander Bolozdynya

Coimbra University Jose Matias Lopes, Luis Coelho, Luis Fernandes and Joaquin Santos

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Lawrence Livermore National Laboratory Adam Bernstein, Chris Hagmann, Norm Madden and Celeste Winant

LNGS Francesco Arneodo and Alfredo Ferella

Rice University Uwe Oberlack, Roman Gomez, Christopher Olsen and Peter Shagin

RWTH Aachen University Laura Baudis, Jesse Angle, Joerg Orboeck, Aaron Manalaysay and Stephan Schulte

Yale University Daniel McKinsey, Louis Kastens, Angel Manzur and Kaixuan Ni

